Appl. No. Unassigned; Docket No. NL03 0806 US Amdt. dated December 13, 2005 Preliminary Amendment

Amendments to the Specification

In the Abstract, please amend the following.

ABSTRACT:

Consistent with example embodiments, there is a system and method A system and method for providing a built-in characterization of a semiconductor device. The device is provided with a built-in, integral, characterization unit which allows characterization allowing characterization of the device without the need for external test equipment.

Fig. 2